Atty Docket No. LAM1P128
Application No.: 09/440,794
Applicant Bailey III et al. APR 1 9 2 001

Filing Date November 15, 1999
Group 1765
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U.S. Patent Documents

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Other Documents

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MA	L.	Japanese Application No. 04094953, filed March 1992, entitled "PLASMA DAMAGE REDUCTION AND PLASMA PROCESSOR," by Minegishi Kazushige, Patent Abstracts of Japan, Vol. 18, No. 33
MA	M.	Japanese Application No. 08255259, filed August 1996, entitled "SHALLOW MAGNETIC FIELD FOR IMPROVING PLASMA PROCESSING BY THE CIRCULATION OF ELECTRONS," by Michael Welch, Patent Abstracts of Japan, Vol. 1999, No. 7.
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Form 1449 (Modified) Information Disclosure O 2000 Statement By Applicant PACEMAND Se Several Sheets if Necessary)

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